

**Notice of References Cited**

Application/Control No.

09/412,328

Applicant(s)/Patent Under

Reexamination

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Examiner

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Art Unit

2814

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	D	US-			
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Hodges et al. " Analysis and desing of Integrated Circuits" 1988, McGraw-Hill, pp 368, 369.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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